

SOLID STATE PHYSICS

FYSC13: Powder X-ray Diffraction Lab

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LUND
UNIVERSITY

OUTLINE

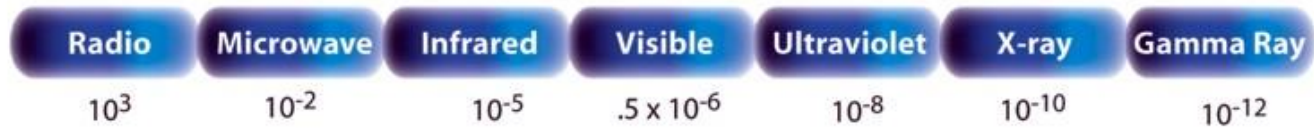
- Short introduction to X-ray Diffraction
- Crystal structure
- Diffraction patterns analysis
- Experiments

THE ELECTROMAGNETIC SPECTRUM

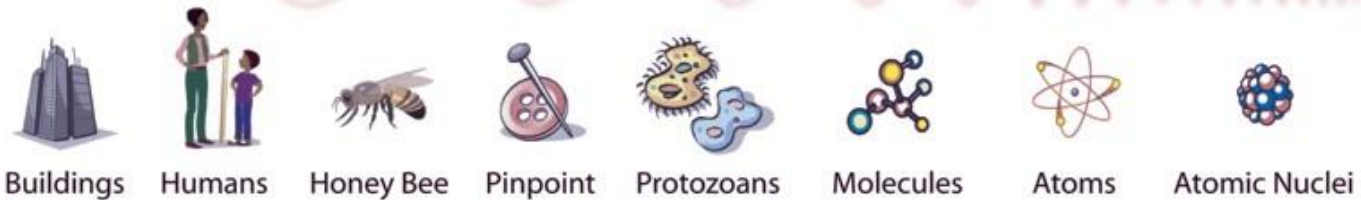
Penetrates
Earth
Atmosphere?



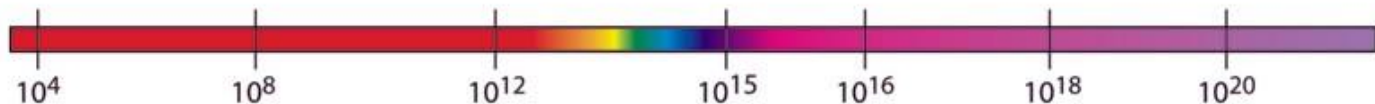
Wavelength
(meters)



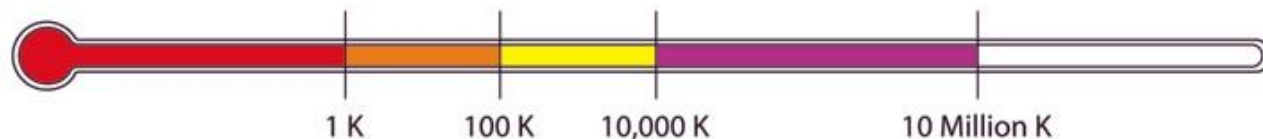
About the size of...



Frequency
(Hz)



Temperature
of bodies emitting
the wavelength
(K)



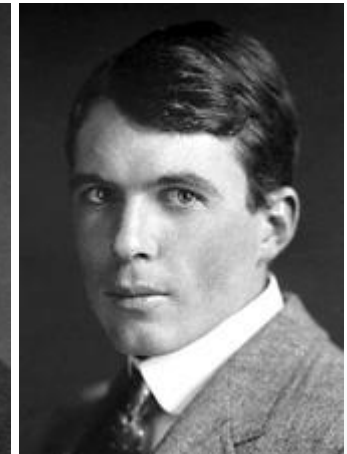
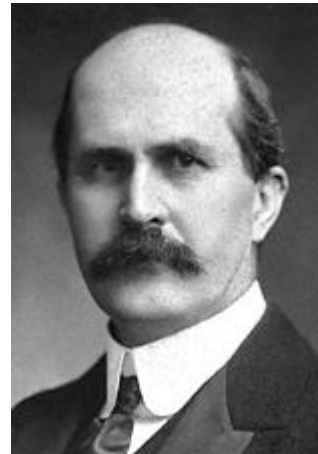
DISCOVERY OF X-RAY DIFFRACTION

1895 Wilhelm Conrad Röntgen
discovers X-rays



1912 Max Theodor Felix von Laue
invents X-ray diffraction

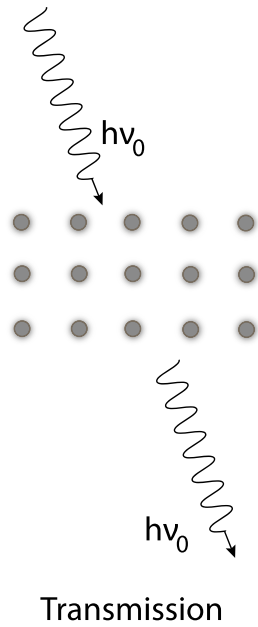
1912 Sir William Henry Bragg
William Lawrence Bragg
determine the crystal structure of NaCl, ZnS,
and diamond; Bragg's law is derived



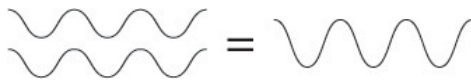
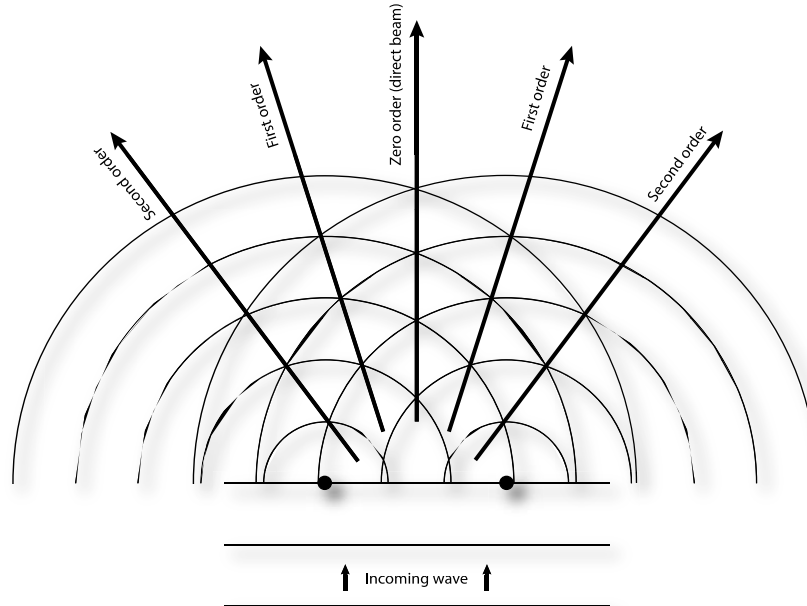
NOBEL PRIZES

Year	Prize	Awardee	Topic
1901	Physics	W. C. Röntgen	Discovery of X-rays
1914	Physics	M. Von Laue	Discovery of XRD
1915	Physics	W. H. Bragg W. L. Bragg	Analysis of crystal structure using XRD
1962	Chemistry	J. C. Kendrew M. F. Perutz	Structural determination of globular proteins (myoglobin and hemoglobin)
1964	Chemistry	D. C. Hodgkin	Structure determinations of important biochemical molecules
1962	Medicine	F. H. Crick J. D. Watson M. H. Wilkins	Structure of DNA
1988	Chemistry	J. Deisenhofer R. Huber H. Michel	Structure of photosynthetic reaction center

BASIC INTERACTION PROCESSES



INTERFERENCE PATTERN



*Constructive interference
(increase of amplitude)*



*Destructive interference
(decrease of amplitude)*

LASER THROUGH DOUBLE SLIT

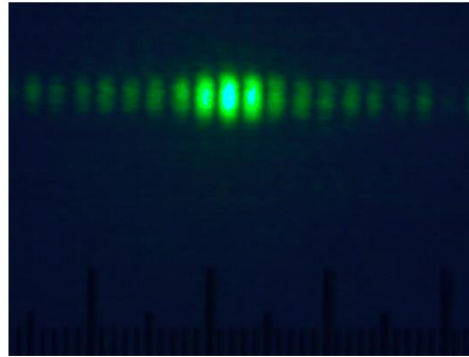
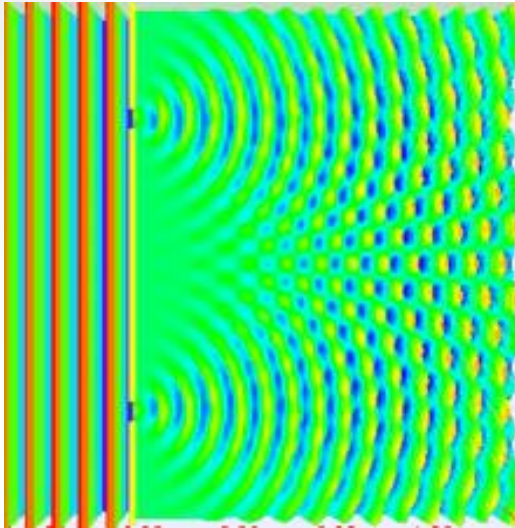


Figure 4.13: Interference pattern with green light

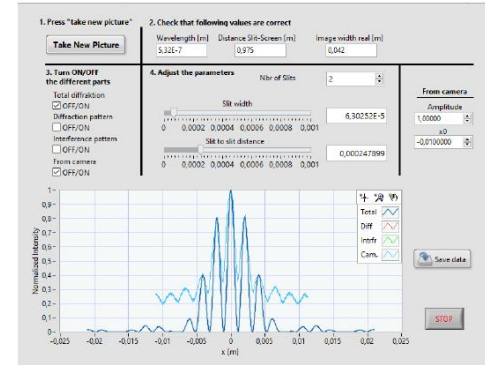
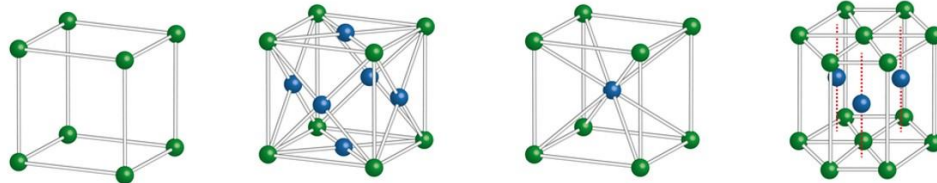
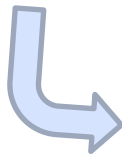


Figure 4.14: Computer modelling (green light)



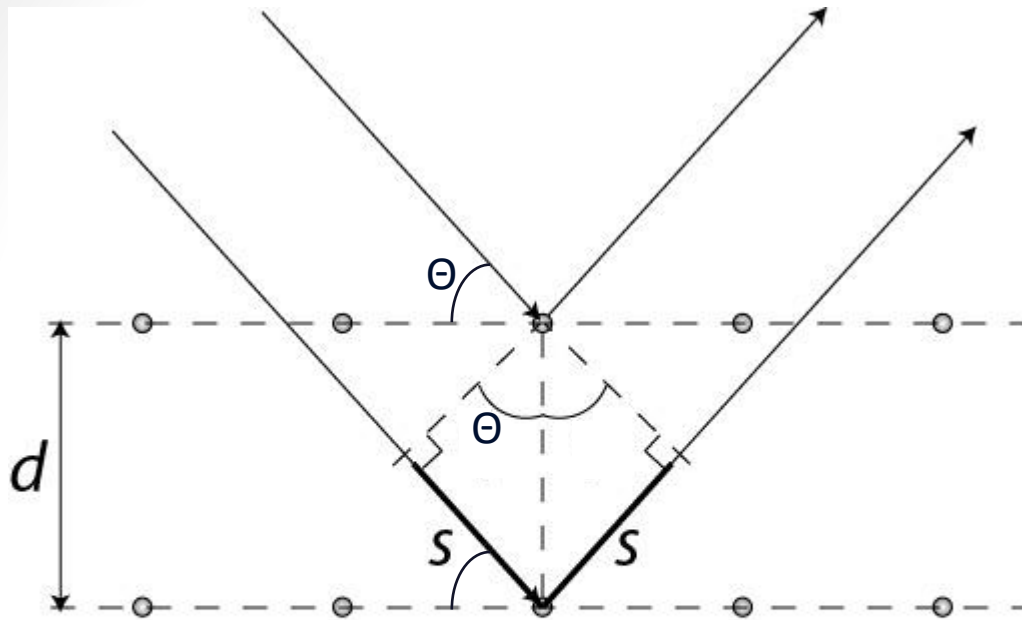
λ (visible light) \approx a (slits gap)



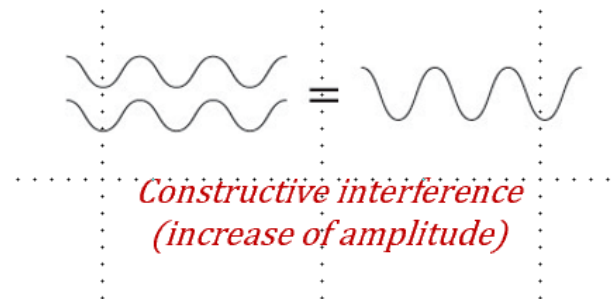
shutterstock.com · 208234940

λ (X-ray) \approx a (lattice parameter)

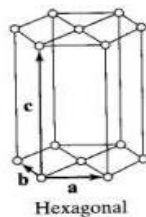
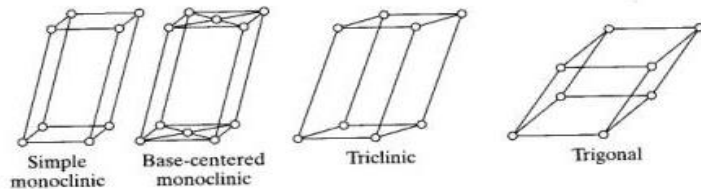
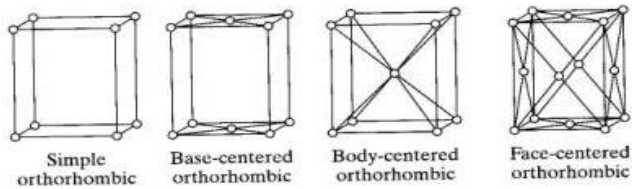
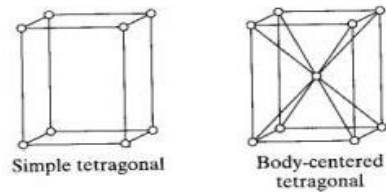
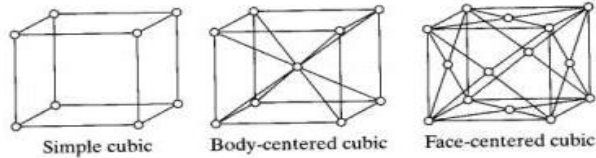
BRAGG'S LAW



$$n\lambda = PD = 2s = 2d \sin\theta$$



CRYSTAL LATTICE



Auguste Bravais

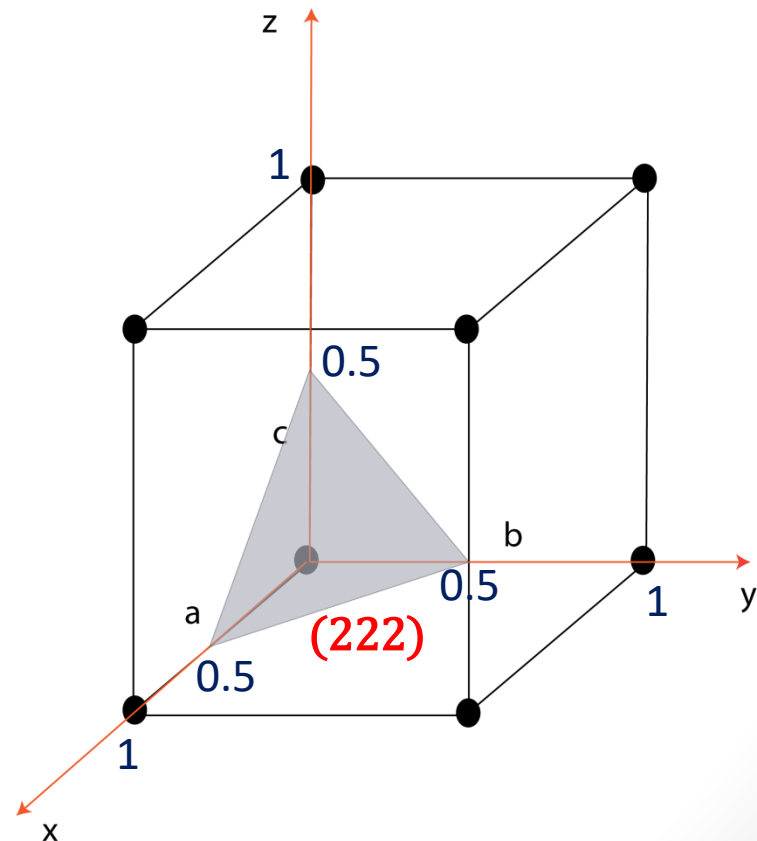
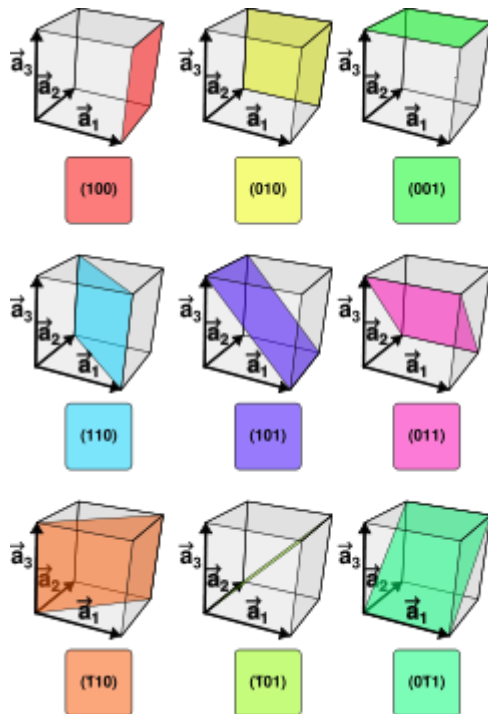
A *crystal lattice* is an array of lattice points.

The *unit cell* is unit of the translationally repeating pattern.

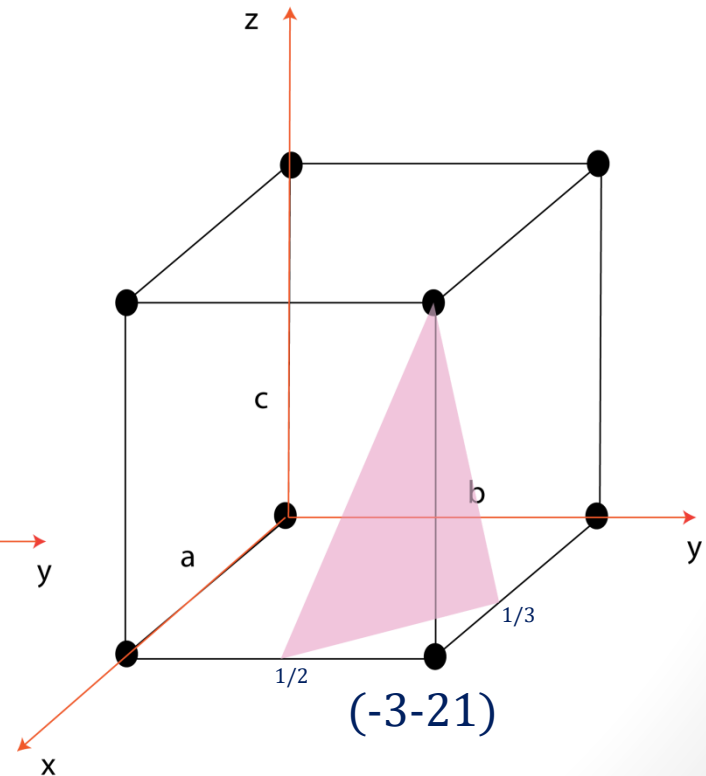
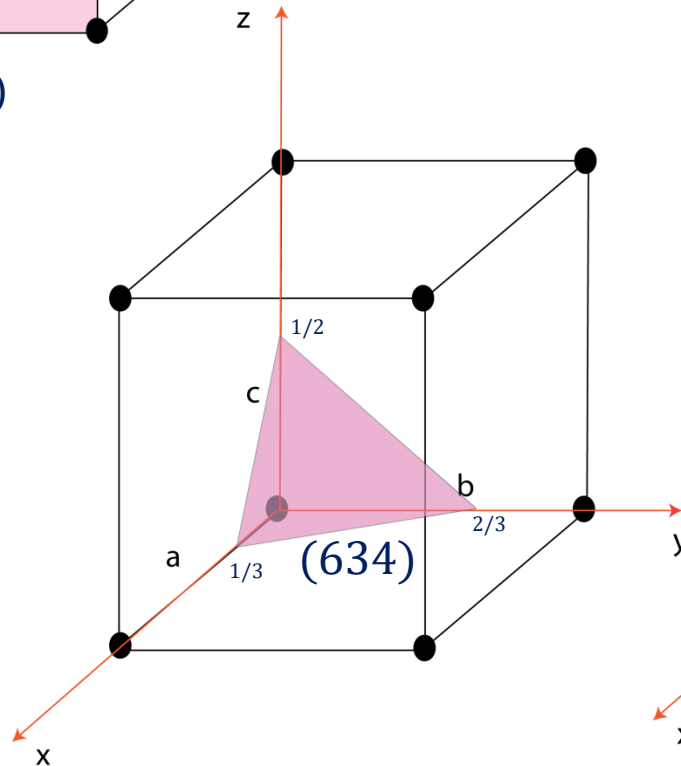
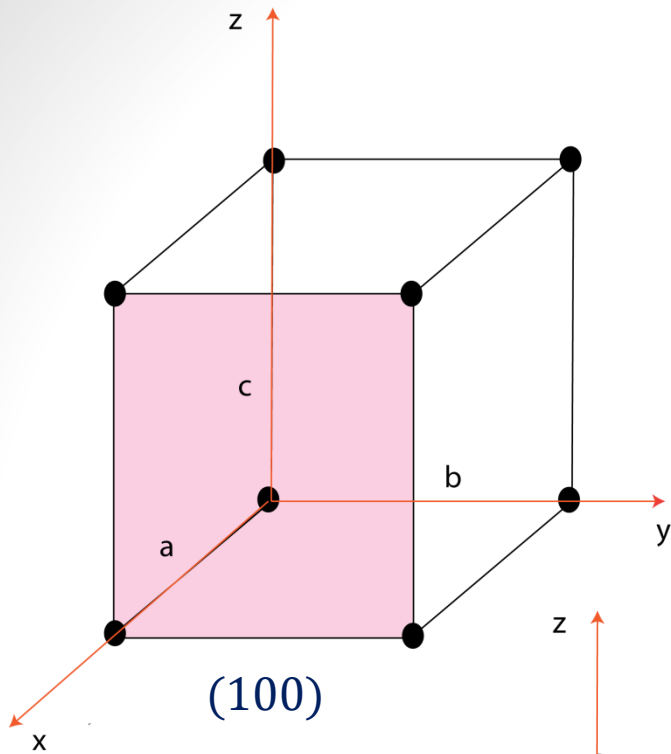
NOTATION OF PLANES

Miller indices describe the orientation of a plane or set of planes within a lattice in relation to the unit cell.

Miller indices are the reciprocals of intersection distances.

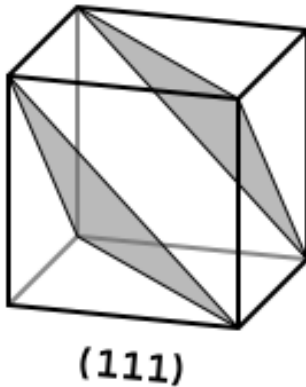


Miller indices should be integer numbers, thus if we are getting fractions for h , k , l values, we need to reduce them to lowest common denominator.



SEPARATION OF PLANES

The distance between planes of atoms can be calculated as

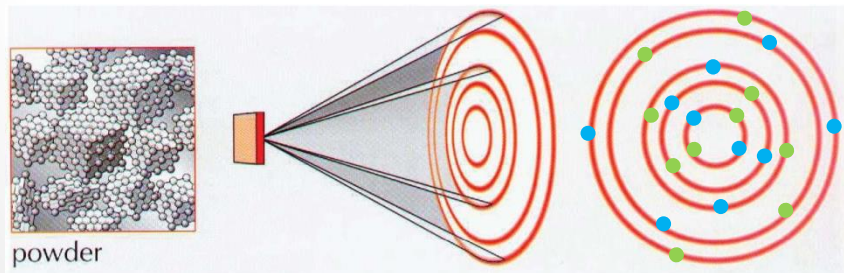
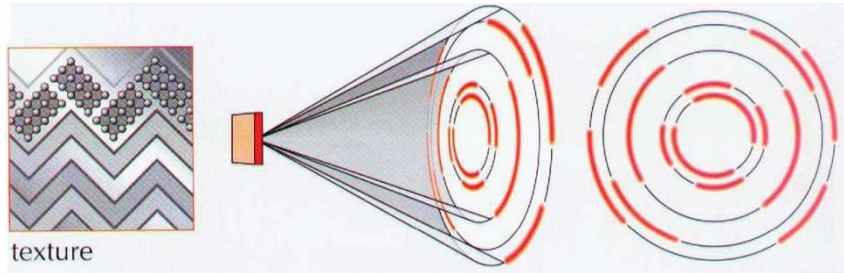
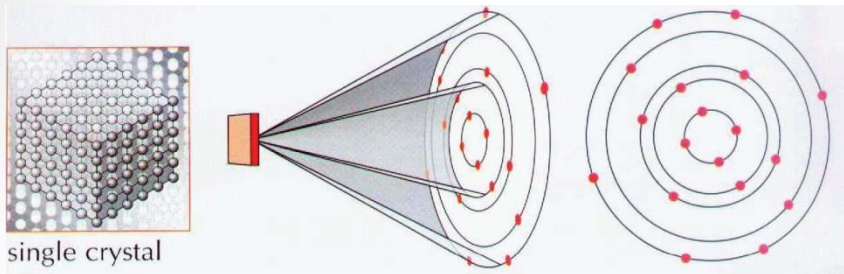


$$\frac{1}{d^2} = \frac{h^2}{a^2} + \frac{k^2}{b^2} + \frac{l^2}{c^2}$$

For cubic cell:

$$\frac{1}{d^2} = \frac{h^2 + k^2 + l^2}{a^2} \quad \text{or} \quad d = \frac{a}{\sqrt{h^2 + k^2 + l^2}}$$

TYPES OF X-RAY DIFFRACTION PATTERNS

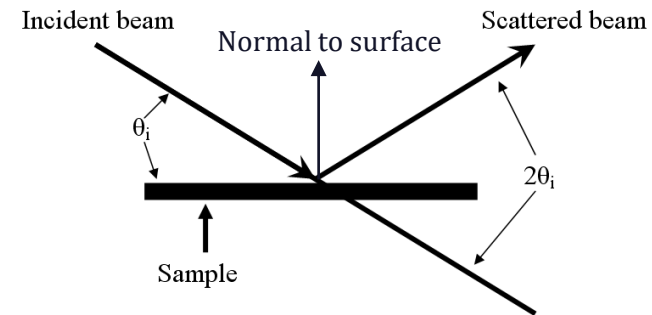
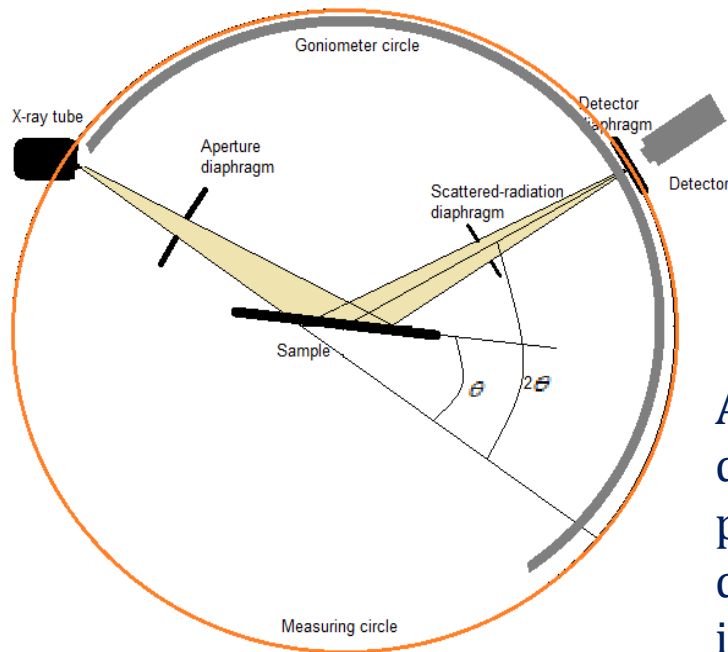


In powder sample we will have all possible orientations of crystallites and some of them will be orientated in a proper way to give rise to diffracted intensity at the glancing angle θ .

The crystallites with this glancing angle will lie at all possible angles around the incoming beam (azimuthal angles), so the diffracted beams lie on a cone around the incident beam of half-angle 2θ .

θ - 2θ SCAN

For structural characterization of crystalline compounds.

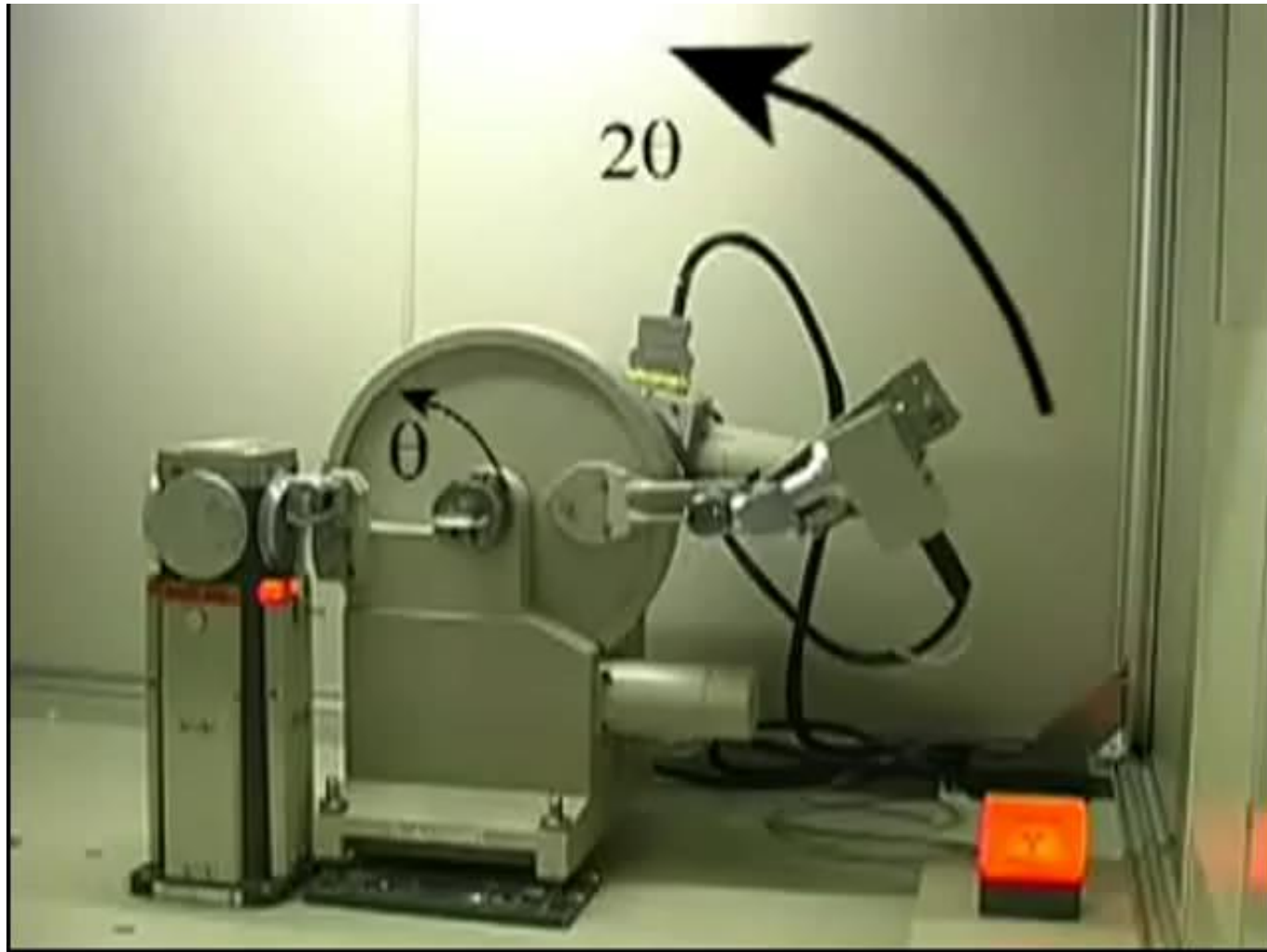


A diffraction peak is observed in a certain direction from a sample if there are crystal planes which can reflect X-rays in that direction, and if the reflected X-rays interfere constructively.

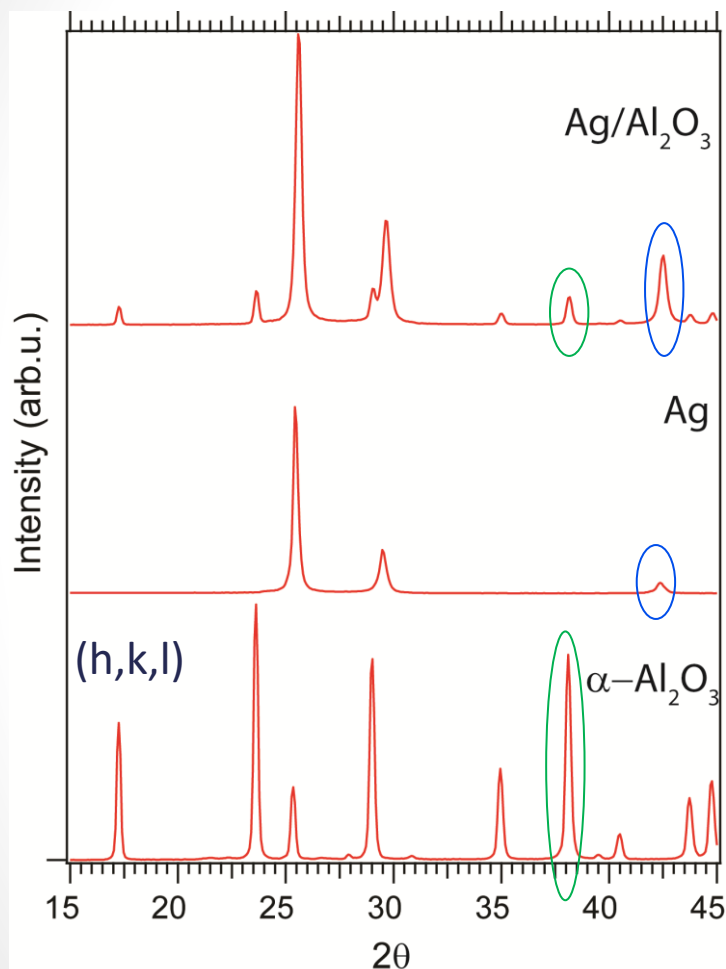
When X-ray beam hits a sample and is diffracted we can measure the distances between the planes of the atoms that constitute the sample

$$n\lambda = 2d \sin \theta$$

POWDER X-RAY DIFFRACTOMETER



DATA ANALYSIS



1. Calculation of d and/or a for particular planes

$$n\lambda = 2d\sin\theta$$

2. Calculation of relative concentration of components in case of multicomponent sample

Measuring relative intensity of strong non-overlapping maxima belonging to different species.

3. Calculation of size of crystallites

$$t = \frac{k\lambda}{\beta\cos\theta} - \text{Scherrer's formula}$$

t – mean size of ordered domains (crystallites),
 k – shape factor (=0.94 for our case), β – FWHM (full width at the half of maximum) in radians.

DATA ANALYSIS

4. Calculation of allowed hkl values, that will give Bragg points on the diffraction pattern

Structure factor (mathematical description of how a material scatters incident radiation)

$$F(hkl) = \sum_m f_m \exp(2\pi i(a_1 h + a_2 k + a_3 l))$$
$$I_{\text{peak}} \sim F^2$$

a_i - real space coordinates of unit cell atoms taken in terms of unit cell basis

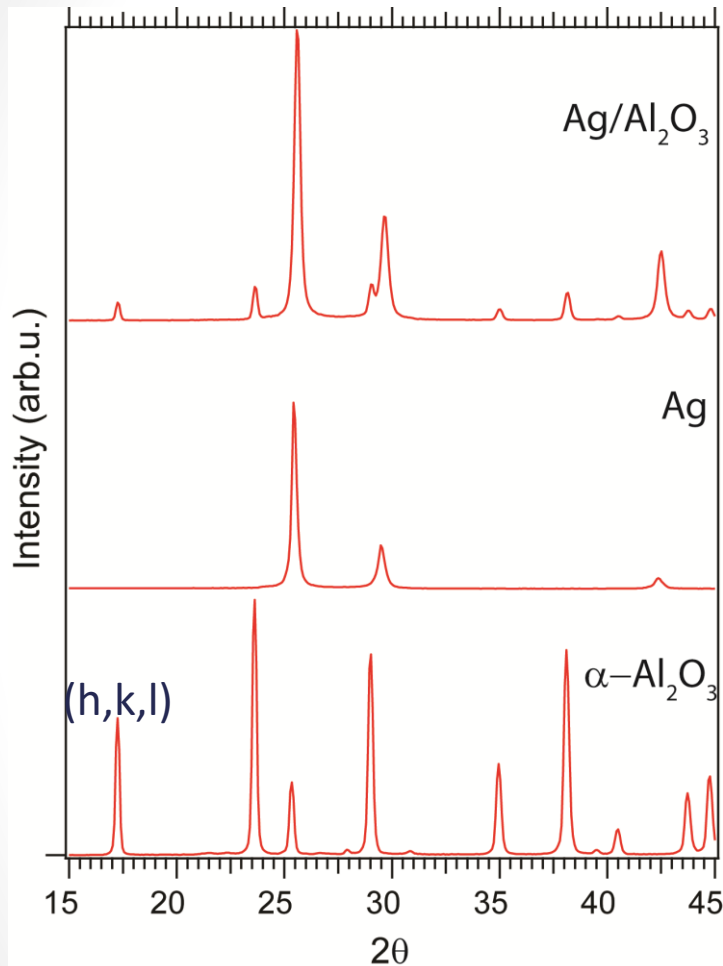
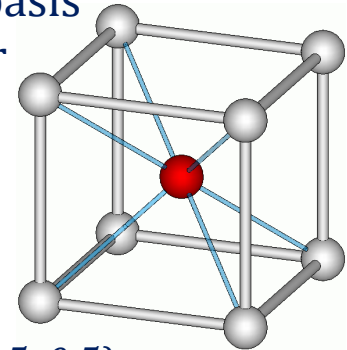
f_m - atomic scattering factor

Example:

BCC unit cell contains

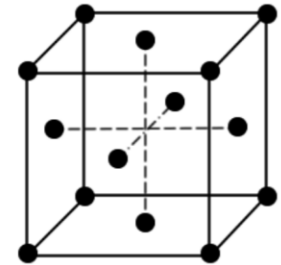
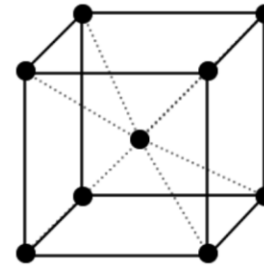
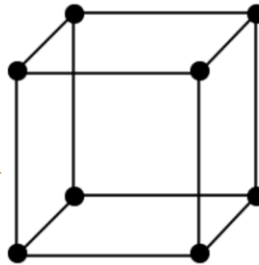
atoms with

coordinates $(0, 0, 0)$ and $(0.5, 0.5, 0.5)$



Then if we do the calculation for “I”,
For BCC, for all (hkl) planes, x-ray intensity
is non-zero except when $h+k+l$ is odd

Different lattice types



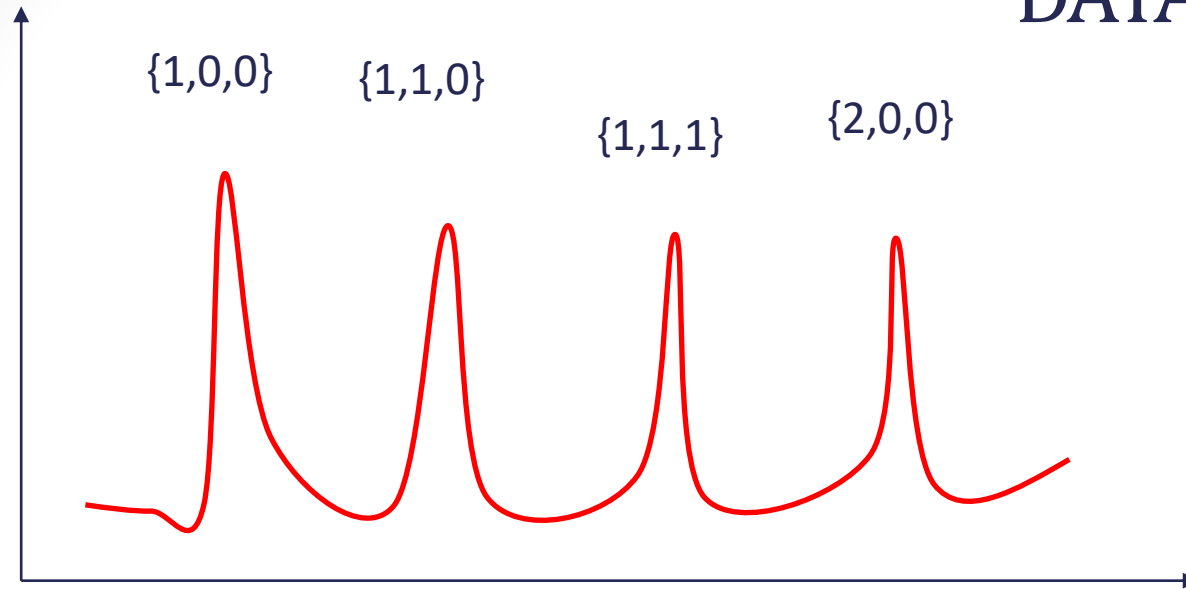
Body centered

$$\begin{aligned}\sum_n e^{i\mathbf{Q}\cdot\mathbf{r}_n} &= e^{i\mathbf{Q}\cdot\mathbf{0}} + e^{i\mathbf{Q}\cdot(\frac{1}{2}\mathbf{a}_1 + \frac{1}{2}\mathbf{a}_2 + \frac{1}{2}\mathbf{a}_3)} = 1 + e^{i(h\mathbf{b}_1 + k\mathbf{b}_2 + l\mathbf{b}_3)\cdot(\frac{1}{2}\mathbf{a}_1 + \frac{1}{2}\mathbf{a}_2 + \frac{1}{2}\mathbf{a}_3)} \\ &= 1 + e^{i2\pi\frac{1}{2}(h+k+l)} = \left\{ \begin{array}{l} \text{Solve this yourself!} \end{array} \right.\end{aligned}$$

Face centered

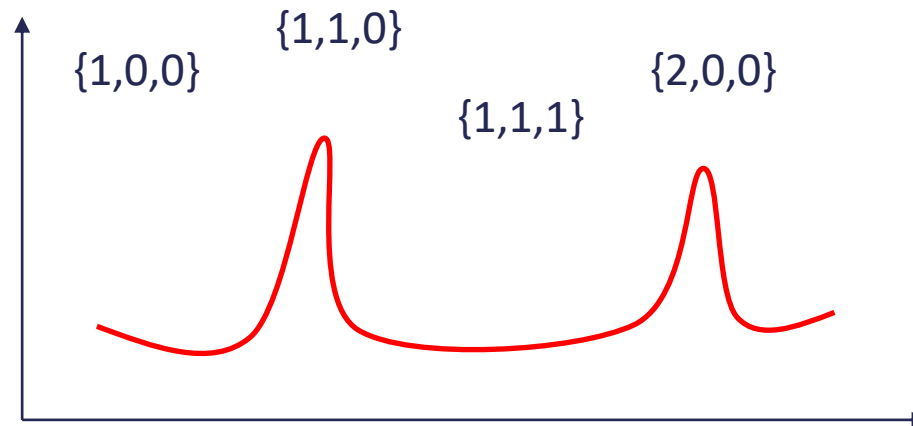
$$\begin{aligned}\sum_n e^{i\mathbf{Q}\cdot\mathbf{r}_n} &= e^{i\mathbf{Q}\cdot\mathbf{0}} + e^{i\mathbf{Q}\cdot(\frac{1}{2}\mathbf{a}_1 + \frac{1}{2}\mathbf{a}_2)} + e^{i\mathbf{Q}\cdot(\frac{1}{2}\mathbf{a}_1 + \frac{1}{2}\mathbf{a}_3)} + e^{i\mathbf{Q}\cdot(\frac{1}{2}\mathbf{a}_2 + \frac{1}{2}\mathbf{a}_3)} \\ &= 1 + e^{i2\pi\frac{1}{2}(h+k)} + e^{i2\pi\frac{1}{2}(h+l)} + e^{i2\pi\frac{1}{2}(k+l)} \\ &= \left\{ \begin{array}{l} \text{Solve this yourself!} \end{array} \right.\end{aligned}$$

SC structure



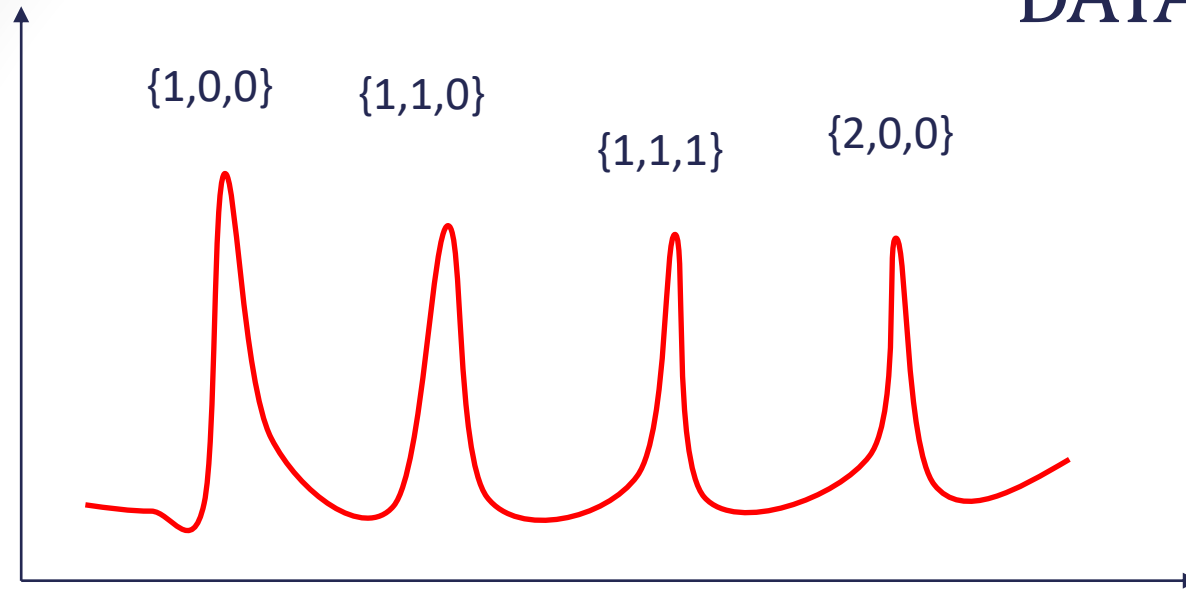
DATA ANALYSIS

BCC structure

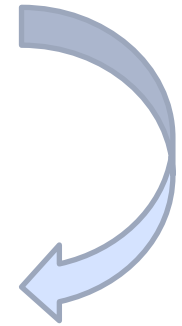
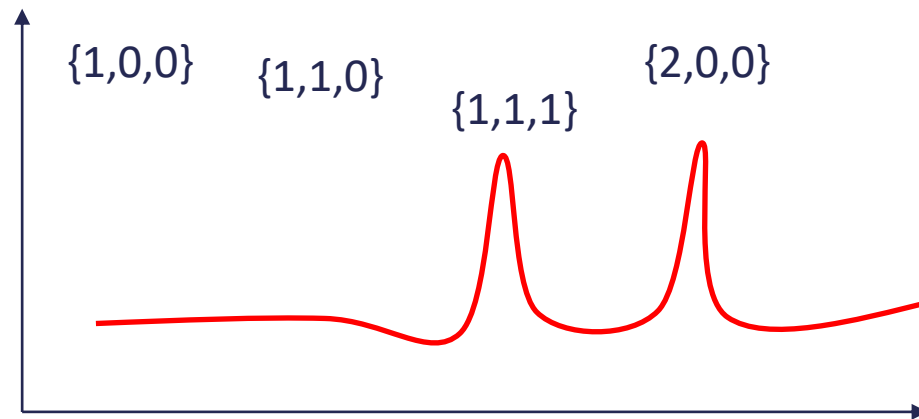


The order of peaks is by values obtained by: $\sqrt{(h)^2 + (k)^2 + (l)^2}$

SC structure



FCC structure



The order of peaks is by values obtained by: $\sqrt{(h)^2 + (k)^2 + (l)^2}$

DATA ANALYSIS

INTEGRATION AND CALIBRATION

